# **XRD Training Notebook**

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February 5, 2019 (rev. 4.1)

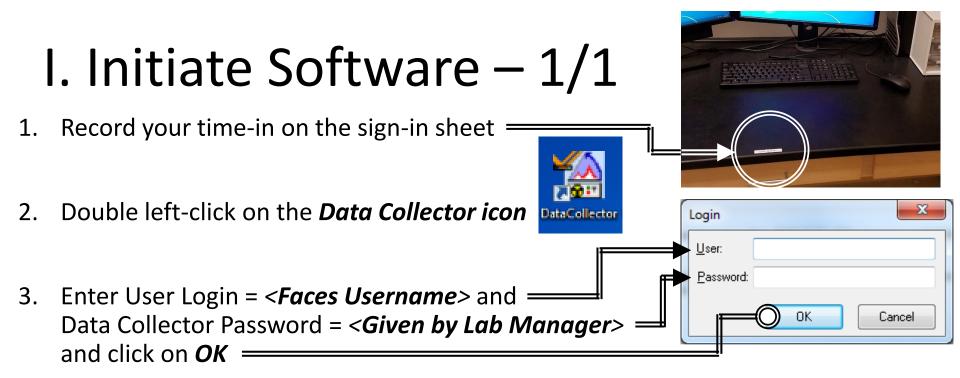
### Before you begin...

- Complete the required safety training modules on UC Learning
  - Laboratory Safety Orientation (Fundamentals) 2013
  - Hazardous Waste Management
  - □ X-Ray Safety
  - Compressed Gas Safety
- Submit a copy of your Training Transcript to Lab Manager
- Review the MSE XRD Policies and Regulations
- Fill out the XRD FAU Authorization Form with PI signature
- Receive a user name and temporary password for Faces scheduling
- Arrange a time for XRD training with Lab Manager
- □ Schedule a 2 hour block on Faces for your training
- Receive a Data Collector password

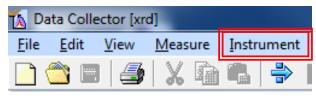
### **XRD** Operation

- I. Initiate Software
- II. Sample Preparation
- III. Membrane Holders
- IV. Irregular Holders
- V. Round Holders
- VI. Sample Loading
- VII. XRD Cabinet
- VIII. X-Ray Settings

- IX. New Measurement Program
- X. Editing Measurement Program
- XI. Start Measurement
- XII. Data Viewing and Exporting
- XIII. Data Analysis
- XIV. Sample Unloading
- XV. Cleanup
- XVI. Troubleshoot



#### 4. Select *Instrument -> Connect*



- 5. Select *Reflection-Transmission Spinner* and click *OK*
- 6. A dialogue box will appear, just click **OK**

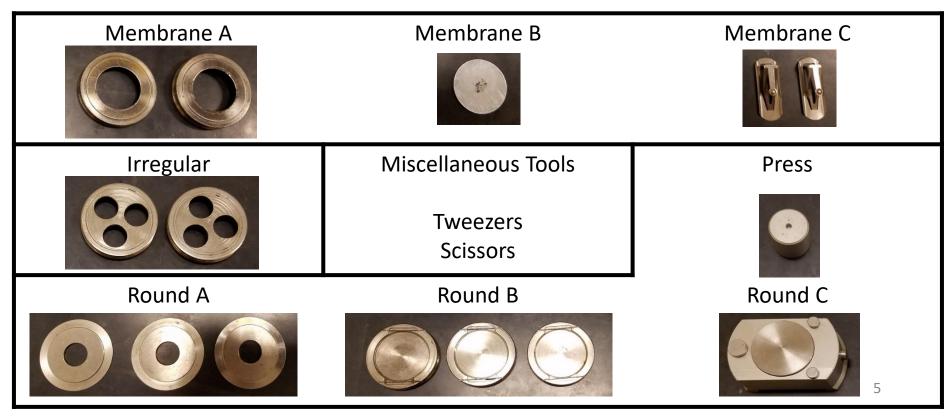
Connect				×
Configuration				ок 🔘
Name	Description	Date	Owner	Cancel
Fiat campio stage		12/4/2012	User-1	
Fiat sample stage Reflection-transmission spinner		12/4/2012	User-1	Help
literation (1997)				F

Data Collector - 9/20/2016 10:06:08 AM	
Assuming incident beam radius:240 mm Assuming Fixed divergence slit with anti-scatter slit. Assuming diffracted beam radius: 240 mm Diffracted PreFIX module. Assuming PIXcel with fixed anti-scatter slit.	OK Cancel

## II. Sample Preparation – 1/2

- 1. The sample holder and preparation will vary depending on your sample
- 2. Three types of sample holders are available for use are located in the storage container
- 3. CLEAN UP AFTER EACH USE AND WIPE DOWN!





## II. Sample Preparation – 2/2

- 4. It is important to always have the top of your sample at the SAME height as the top of your sample holder (no exception!)
- 5. If your sample is not at the same height as your sample holder, the peaks obtained will be incorrectly shifted away from correct positions!

Irregular

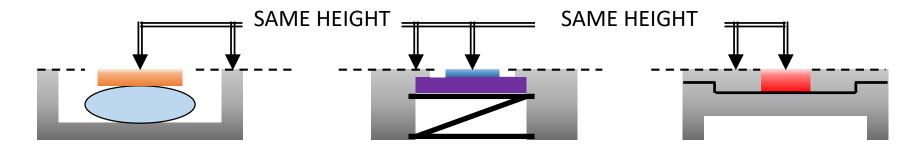


Membrane

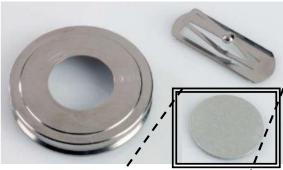








### III. Membrane Holders – 1/1



1. This holder is designed for mounting:

- dust filters
- sample mounting plates
- metal plates
- pressed pellets
- silicon substrates
- 2. Requires a support plate (Diameter = 32 mm)
  - Aluminum support provided (will have background Al peaks)
  - Recommend Si Zero Background Plate
    - These need to be provided by users

MTI Corp: Zero Diffraction Plate 32 mm Dia. x 2.0 mm t, Si Crystal for XRD sample (\$150)

MTI Corp: Zero Diffraction Plate with Cavity for XRD sample: 32 Dia x 2.0 t mm with Cavity 10 ID x 0.2 mm, Si Crystal (\$199)



Warning: X-ray beam shall be 5 mm dia or less (<u>current installed beam mask is 10</u> <u>mm</u>) and hit in the center of sample when you use cavity zero diffraction plate! Otherwise the edge may result in a peak. USE AT YOUR OWN RISK!

### IV. Irregular Holders – 1/1



- 1. This holder can be used to analyze solid samples with:
  - Maximum diameter = 45 mm
  - Maximum thickness = 6.5 mm
- 2. The sample can be mounted with clay available from Storehouse:



- Storehouse Description: <u>SARGENT ART 22-4096 1LB MODELING</u> <u>CLAY, WHITE (Stock #: 48702-108)</u>
- 3. Recommend using a glass slide or Si zero background plate as support for your sample on top of clay



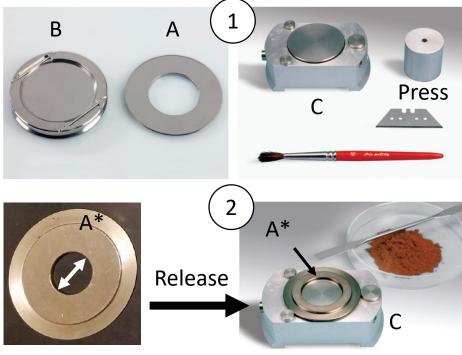
MTI Corp: Zero Diffraction Plate 32 mm Dia. x 2.0 mm t, Si Crystal for XRD sample (\$150)

MTI Corp: Zero Diffraction Plate with Cavity for XRD sample: 32 Dia x 2.0 t mm with Cavity 10 ID x 0.2 mm, Si Crystal (\$199)



Warning: X-ray beam shall be 5 mm dia or less (<u>current installed beam mask is 10</u> <u>mm</u>) and hit in the center of sample when you use cavity zero diffraction plate! Otherwise the edge may result in a peak. USE AT YOUR OWN RISK!

## V. Round Holders – 1/2



Diameter = 16 mm





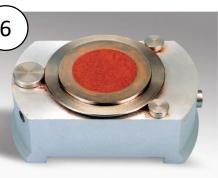
 Assemble the items for powder samples (user provides razor and brush)

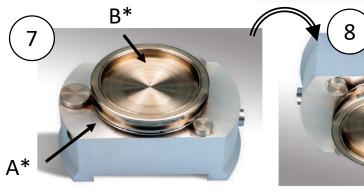
#### REMEMBER TO CLEAN ALL SURFACES FIRST BEFORE USING!

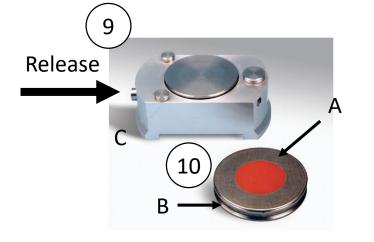
- Invert A to get A\*. Place on top of C and push the release to have it sit into place.
- 3. Spread the powder into the cavity using a spatula but do not pack or compress.
- 4. Press powder with Aluminum press

## V. Round Holders – 2/2







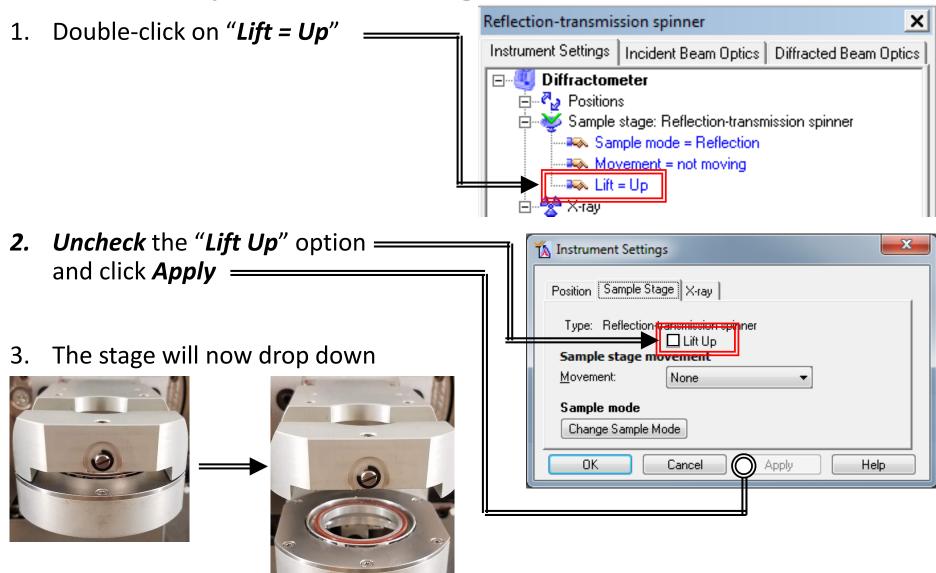


5. Remove excess powder with a straight edge or side of microscope slide

#### DO NOT SCRATCH TOP SURFACE!

- 6. Clean mating surfaces with small brush or provided kim wipe
- Invert B to get B\* and snap on top of A\*
- 8. Flip entire assembly
- 9. Push the release to remove the sample holder (A + B) from C
- 10. The surface of your sample should be smooth via back-filling approach

## VI. Sample Loading – 1/4



## VI. Sample Loading – 2/4

4. Press "UNLOCK DOORS" on cabinet =

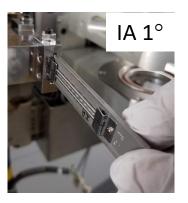
5. Open doors by pulling on the handles at the ends for better leverage \_\_\_\_\_

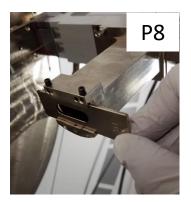




- 6. Inspect and check if desired slits are installed
  - Standard Slits are default:
    - Inc Div ½°
    - Inc Ant 1°
    - Dif Ant **P8**



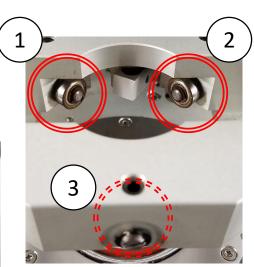




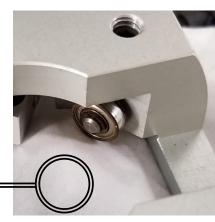
## VI. Sample Loading – 3/4

- Inspect Stage for any residual sample left stuck on 3
   Spinner Bearings from previous user
- 8. Take *Kimwipe* with *IPA* and carefully wipe all *3 Spinner Bearings*
- 9. Use fresh area on *Kimwipe* to remove residual sample
- Fold, and use fresh area of *Kimwipe* to wipe down the base of the *Stage*
- 11. If necessary, use provided *Air Duster* to dry and remove any remaining dust on *Stage*









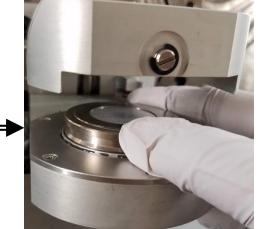
### VI. Sample Loading – 4/4

12. Carefully insert *Sample Holder* into *Stage* 









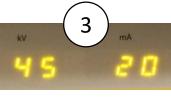
13. Confirm *Sample Holder* is properly seated into *Stage* 

	🔥 Instrument Settings
14. Close doors of cabinet	Position Sample Stage X-ray
	Type: Reflection transmission spinner           Image: Sample stage movement
	Movement: None -
15. Check the "Lift Up" option and click Apply	Sample mode Change Sample Mode
	OK Cancel Apply Help
16. Click <i>OK</i>	

## VII. XRD Cabinet – 1/5

- Always remember to check
   3 indicators that XRD is **OK**
  - White Power Light is On
  - X-Rays On Light is On
  - X-Ray settings are 45 kV and 20 mA





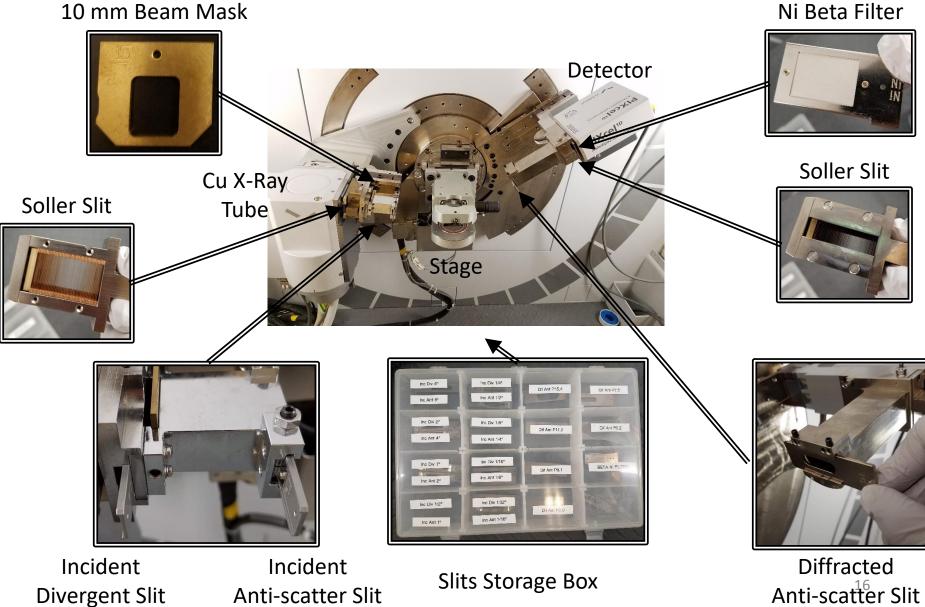
#### Note: If above 3 indicators are missing, contact Lab Manager



Lights On Button

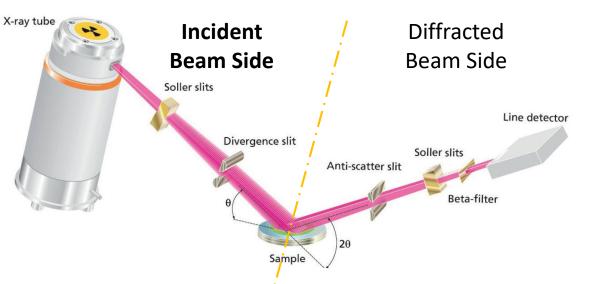
#### VII. XRD Cabinet – 2/5

Ni Beta Filter



## VII. XRD Cabinet – 3/5

The following table describes the components for the **Incident Beam Side** 

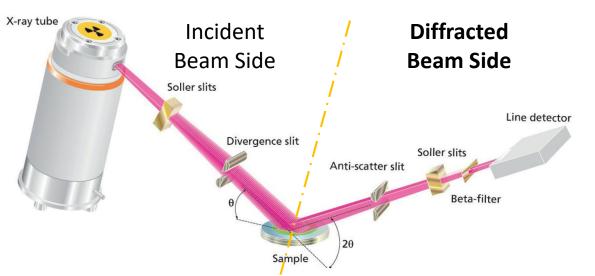


#### **Incident Beam Side**

Component Name	Function or Description
Soller Slit	Prevents axial divergence and improves peak shape and symmetry
Divergence Slit	Controls the irradiated length of the X-Ray beam on the sample. Slit size depends on sample size and starting scan angle.
Incident Anti-scatter Slit	Reduces X-Ray beam scatter and reduces background. Typically double the selection of the divergent slit.
Beam Mask (not pictured)	Controls axial width of the X-Ray beam. Match to sample size. $17$

## VII. XRD Cabinet – 4/5

The following table describes the components for the **Diffracted Beam Side** 



#### **Diffracted Beam Side**

Component Name	Function or Description
Receiving Slit	Controls the resolution of the instrument, common setting is 0.1 mm.
Soller Slit	Match with incident selection, typically 0.04 radians.
Diffracted Anti- scatter Slit	Match to the selection of the Divergent Slit.
Beta-filter	Used to remove beta radiation.
Detector	PIXcel 1D 18

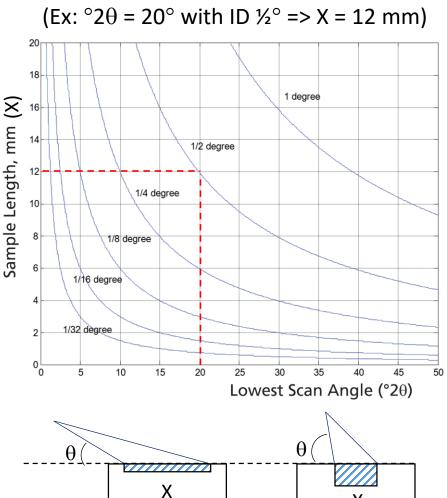
### VII. XRD Cabinet – 5/5

#### Standard Slit Configuration = $1/2^{\circ}$ , $1^{\circ}$ , 8 mm

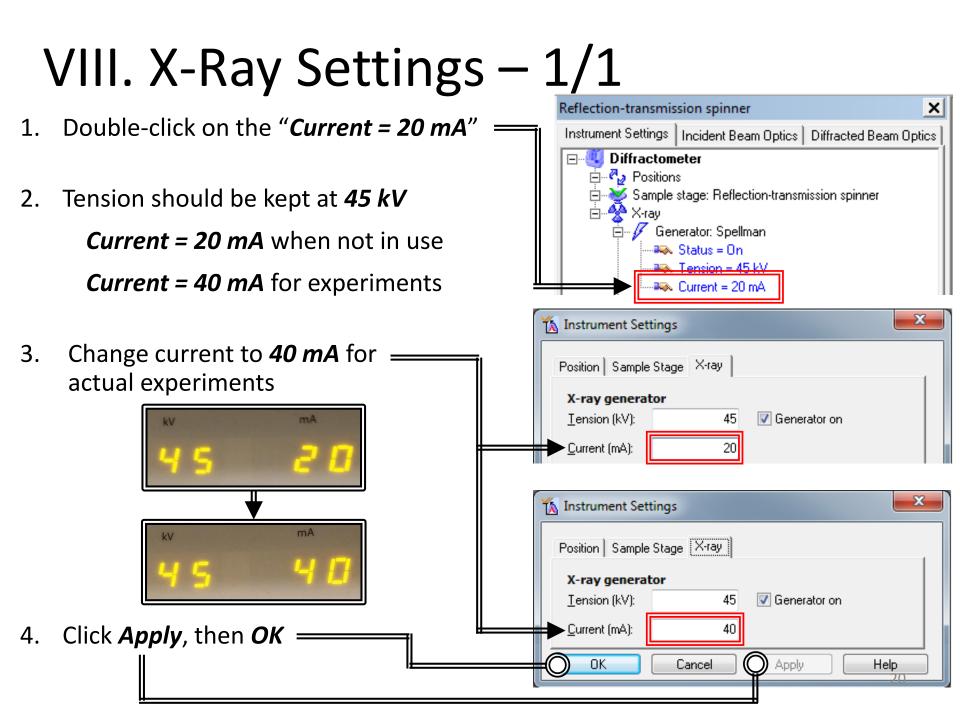
Effects of Low Scan Angles: *Irradiated Sample Length X* vs. °2θ

Slit Configurations							
Incident E	Beam Side	<b>D</b> iffracted Beam Side					
Incident Divergence	Incident <b>A</b> nti-scatter	Diffracted Anti-scatter					
ID 4°	IA 8°	P15.4	1				
ID 2°	IA 4°	P11.2					
ID 1°	IA 2°	P9.1	•				
ID <b>1/2°</b>	IA 1°	P8.0					
ID 1/4°	IA 1/2°	P7.5					
ID 1/8°	IA 1/4°	P7.5					

Choose smaller slit sizes for removing background intensity at low angles

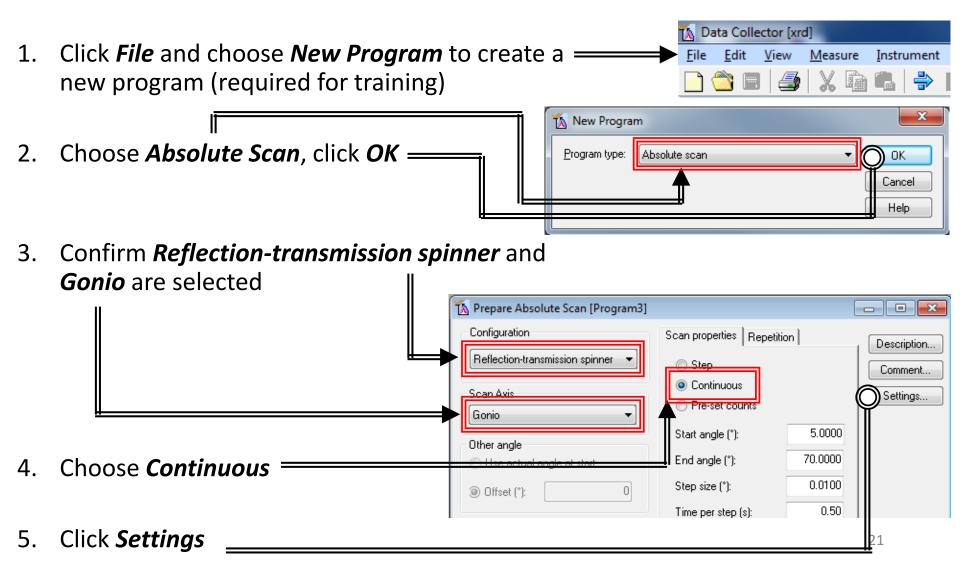


Decreasing Slit Size



#### IX. New Measurement Program – 1/7

Note: SKIP to X. Editing Measurement Program if you already have a program



#### IX. New Measurement Program – 2/7

#### 6. Click *Movement*

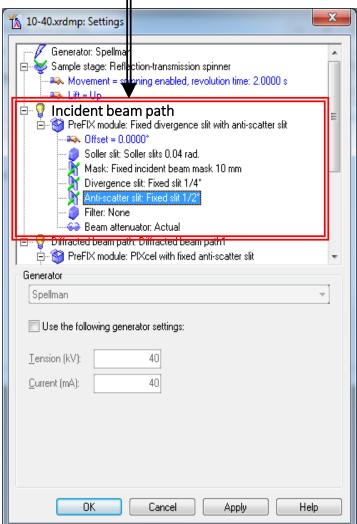
- Set to *Spinning Enabled* (recommended)
  - Set *Revolution Time = 2 seconds*
- Set to *Not moving* if homogeneity is not an issue but sample ejection is

Generator: Spellman Sample stage: Reflection-transmission spinner Movement = not moving	Generator: Spellman Sample stage: Reflection-transmission spinner Movement = spinning enabled, revolution time: 2.0000 s
ple stage movement	Sample stage movement
eflection-transmission spinner 🔹	Reflection-transmission spinner
Spinning Revolution time (s):  Oscillation Not moving	<ul> <li>Spinning</li> <li>Revolution time (s): 2</li> <li>Oscillation</li> <li>Not moving</li> </ul>

7. The default settings show "Actual" (meaningless) for all entries

#### IX. New Measurement Program – 3/7

- 8. Set the following *Incident beam path* entries as follows:
  - □ PreFIX module: *Fixed divergence slit with anti-scatter slit*
  - Soller slit: Soller slits 0.04 rad
  - Mask: Fixed incident beam mask 10 mm
  - Generation Filter: None
  - Beam attenuator: *None*
  - Divergence slit: <<u>Enter what you're using</u>>; if Standard Slits then Fixed slit 1/2°
  - Anti-scatter slit: <<u>Enter what you're using</u>>; if *Standard Slits* then *Fixed slit 1°*

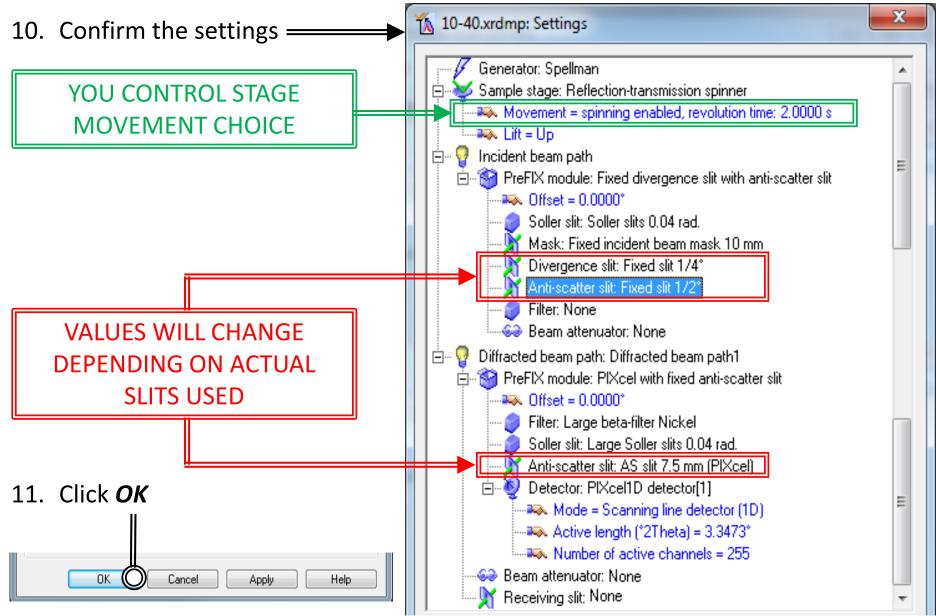


#### IX. New Measurement Program – 4/7

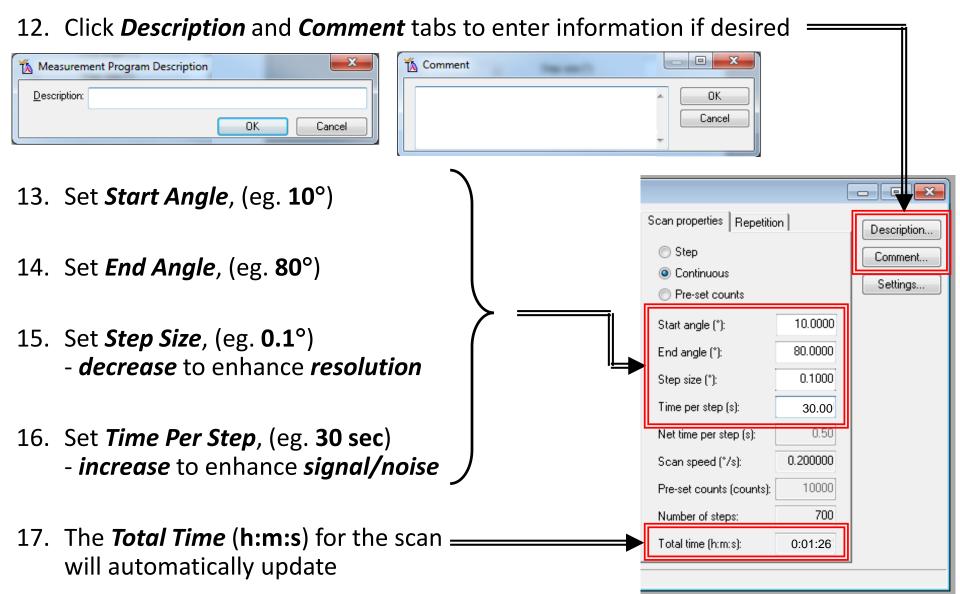
- 9. Repeat for the *Diffracted beam path* entries as follows:
  - □ PreFIX module: *PIXcel with fixed anti-scatter slit*
  - □ Filter: *Large beta-filter Nickel*
  - □ Soller slit: *Large soller slits 0.04 rad*
  - Detector: PIXcel1D detector[1]
  - Beam attenuator: None
  - Receiving slit: None
  - Anti-scatter slit: <<u>Enter what you're using</u>>; if Standard Slits then AS slit 8.0mm (PIXcel)

10-40.xrdmp: Settings	X				
Generator: Spellman Sample stage: Reflection-transmission spinner Movement = spinning enabled, revolution time: 2.0000 s					
Diffracted beam path PreFIX module: PIXcel with fixed anti-scatter slit Offset = 0.0000° Filter: Large beta-filter Nickel Soller slit: Large Soller slits 0.04 rad. Anti-scatter slit: AS slit 7.5 mm (PIXcel) Detector: PIXceI1D detector[1] Mode = Scanning line detector (1D) Active length (*2Theta) = 3.3473* Number of active channels = 255 Beam attenuator: Actual					
Generator Spellman					
Use the following generator settings: Iension (kV): 40 <u>C</u> urrent (mA): 40					
OK Cancel Apply	Help				

#### IX. New Measurement Program – 5/7



#### IX. New Measurement Program – 6/7



#### IX. New Measurement Program – 7/7

- 18. Click the *Close X* to close the window :
- 19. Choose to SAVE your program
- 20. Select your <**PI'S NAME**> folder

W		
🔏 Prepare Absolute Scan [Program4]		
Configuration	Scan properties Repetition	Description
Reflection-transmission spinner 💌	🔘 Step	Comment
Scan Axis	Ontinuous	Settings
	Pre-set counts	

21. Name your *Measurement Program* file

Kopen ↓ Computer →	OS (C:)   PANalytical  Data Collector  Programs	✓ <sup>4</sup> → Search P	Programs		× P
Organize 🔻 New folder					0
☆ Favorites XRD Data	Name PANalytical Training ① 0_klee.xrdmp	Size			
File <u>n</u> ame:			e (*.xrdmp)		-
-		Open		Cancel	

- 22. Default unsorted folder is "C:\PANalytical\Data Collector\Programs"
- 23. Continue to XI. Start Measurement and SKIP X. Edit Measurement Program

#### X. Editing Measurement Program – 1/1

The Data Collector [xrd]

File

Measure

Instrument

The following steps are for **EDITING** existing program you already created only!

**SKIP** to *XI. Start Measurement* if you don't need to edit your program

- 1. Click *File* and choose *Open Program*
- Click *Browse* and find program in <*PI'S NAME*> folder in "C:\PANalytical\Data Collector\Programs"

		🏠 Open						l	x
		00	Computer 🕨 OS (C:)	<ul> <li>PANalytica</li> </ul>	I ▶ Data Collec	• <del>*</del> ;	Search Programs		٩
3.	Click <b>Open</b>	Organize	e ▼ New folder				:==	•	0
		🔶 Favo	orites RD Data	Name	· · · · · ·	Size	2		-
		JA I	File <u>n</u> ame:	JE PANal	ytical Training	•	.xrdmp file (*.xrdm	2)	-
4.	Modify desired parameters —					•	Open 🔽	Cancel	
			K Prepare Absolute Scan [f	Program4]					
5.	Click <i>Close X</i> when done		Configuration		Scan propertie	s Repe	tition	Descript	ion
			Reflection-transmission spir	nner 🔻	🔘 Step			Comme	nt
			Scan Axis		Ontinuo Pre-set o			Setting	IS
6.	Choose to <b>SAVE</b> your program		Gonio		Start angle (		10.0000		
	, , , , ,		Other angle <ul> <li>Use actual angle at start</li> </ul>		End angle (*	):	80.0000		
			Offset (*):	0	Step size (*):		0.1000		
					Time per ste	p (s):	0.50		

#### XI. Start Measurement – 1/3

1.	Select <i>Measure -&gt; Program</i>	ו	
			Data Collector [xrd]
2.	Click <i>Browse</i>		File       Edit       View       Meåsure       Instrument <sup>•</sup>
3.	Default location is "C:\PAN Collector\Programs"	alytical\Data	All
4.	Find your program in < <b>PI'S</b> and click <b>Open</b>	<b>NAME</b> > folder,	Name     Measurement Type     Created by       test PC     Absolute scan     xrd       PP au wafer     Absolute scan     Parawee Pumv       ranytith     Absolute scan     xrd       I     Image: Scan image
			Open BrowseO Close
		<sup>™</sup> Open	► PANalytical ► Data Collector ► Programs ► - 4 Search Programs >
		Organize   New folder	
		★ Favorites ↓ XRD Data	Name Size Size Size Size Size Size Size Siz
		File <u>n</u> ame:	.xrdmp file (*.xrdmp)

## XI. Start Measurement – 2/3

- 5.  $\bigstar$  Click  $\_$  icon to change file location =
- 6. Default is unsorted in "*C:\XRD Data*"
- 7. Select your <**PI'S NAME**> folder
- 8. Select your *Folder* for this scan
- 9. Enter a **Name** for your scan
- 10. Confirm correct *File Folder* location
- 11. Enter a Comment, Sample ID, Sample name, or Username if desired
- 12. Clicking OK will start your scan! —

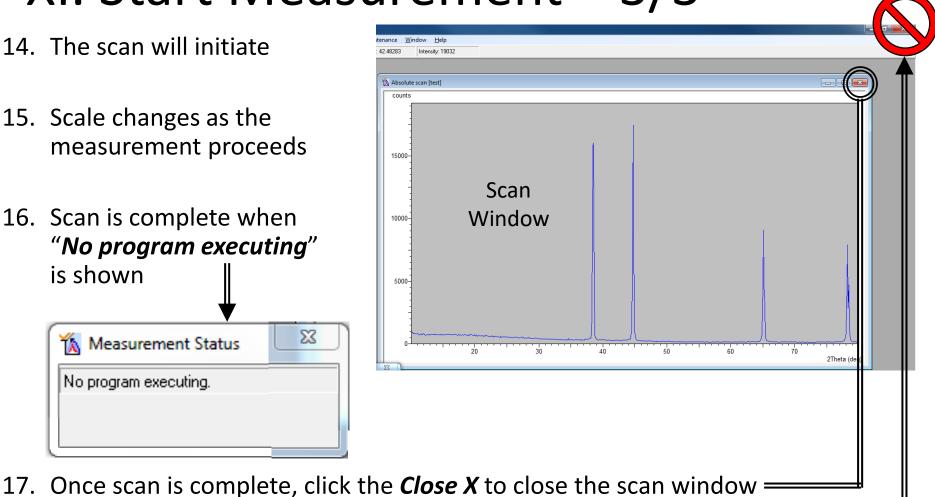
The Start				
	Program			
	Name:	C:\PANalytical\Data Colle\test PC.xrdmp Absolute scan		
	Туре:			
	Description:	test PC		
	File			
	<u>N</u> ame:	test PC_2.xrdml	REQUIRED	r El
	<u>F</u> older:	C:WRD Data		
	<u>C</u> omment:			^ +
	Sample <u>I</u> D:	OPTIONAL		
	<u>N</u> ame:			
	Prepared by:			•
OK Cancel Help				

13. If message appears, perform the actions and click on **OK** 

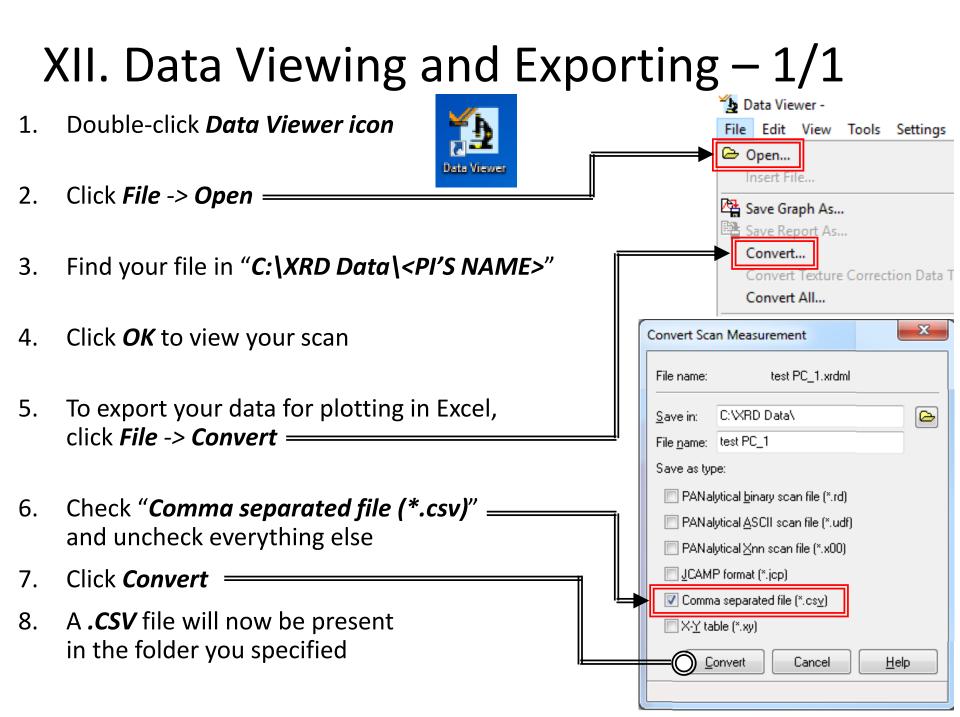
NOTE: THE MESSAGE SHOULD ONLY BE ABOUT CHECKING THAT THE COMBINATION OF SLITS YOU HAVE INDICATED IN YOUR PROGRAM ARE INSTALLED

### XI. Start Measurement – 3/3

- 14. The scan will initiate
- 15. Scale changes as the measurement proceeds
- 16. Scan is complete when "No program executing" is shown 23 🔨 Measurement Status No program executing.



#### 18. DO NOT CLOSE THE DATACOLLECTOR WINDOW



### XIII. Data Analysis – 1/1

#### NOTE: High Score can only be used on "High Score" computer outside

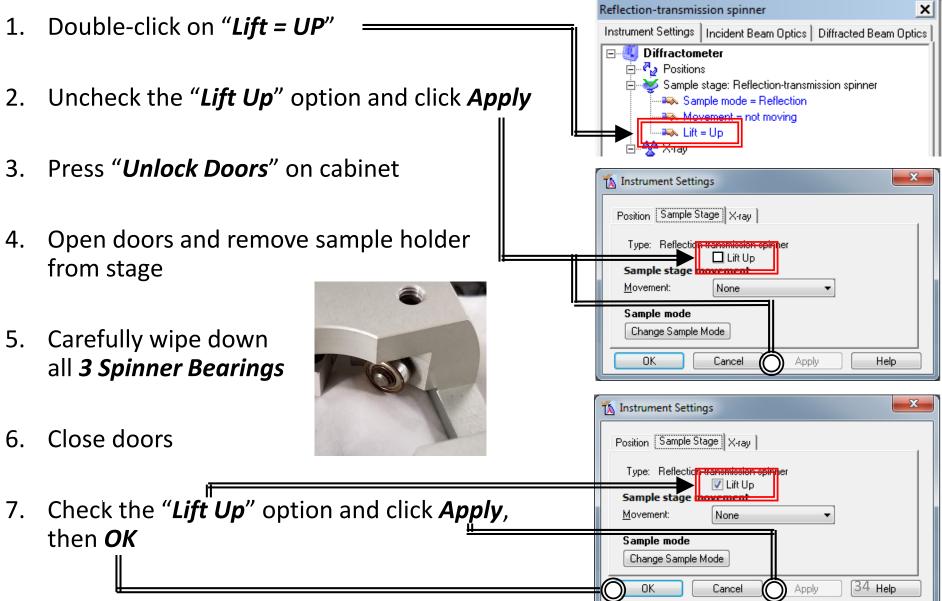
 If you plan on using *High Score*, transfer your files directly to computer outside by transferring them to the "Z" drive directory (computers are networked) or use a flash drive

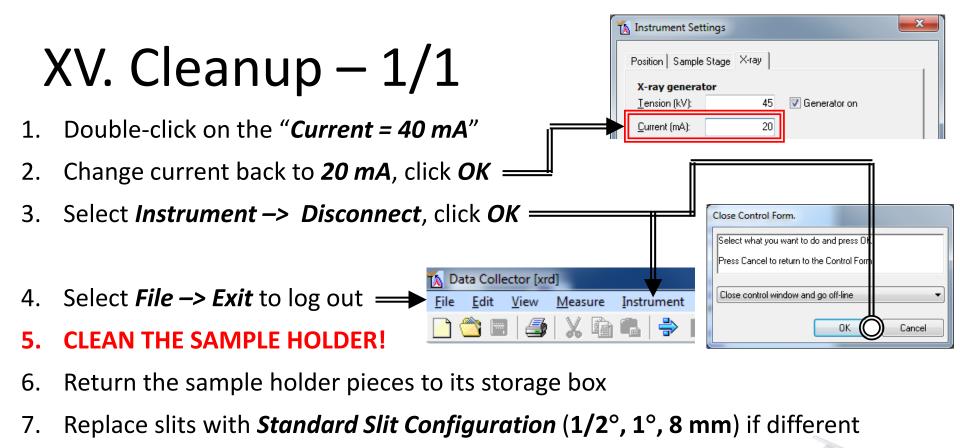




- 2. Refer to "*Introduction to PANalytical X'Pert HighScore Plus v3.0*" guide by Scott A. Speakman available on desktop of "High Score" computer
- 3. Guide is also available on MSE XRD website under Useful Documentation: http://www.mse.ucr.edu/facilities\_xrd.html

## XIV. Sample Unloading – 1/1

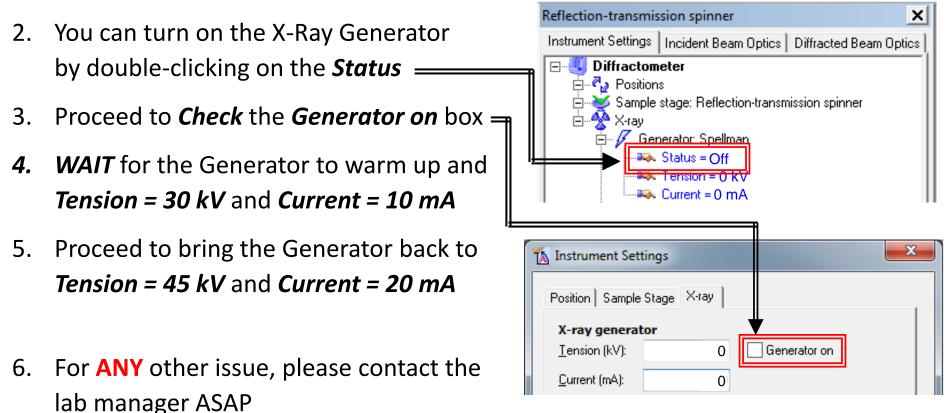




- 8. Return any other used slits back to its storage box
- 9. Brush up any sample that may have dropped into the cabinet
- 10. Turn OFF the lights to the cabinet (if ON)
- 11. Close doors (if open)
- 12. Record your **time-out** on the **sign-in sheet**, slits used, and any issues encountered like dirty sample holders or instrument errors

## XVI. Troubleshoot – 1/1

1. If XRD is powered **ON** but with **Tension = 0 kV** and **Current = 0 mA** ...



- Call the lab manager at (951) 827-3378
- E-mail the lab manager (Perry: <a href="mailto:pcheung@ucr.edu">pcheung@ucr.edu</a>)
- Stop by the lab manager's office at MSE 311